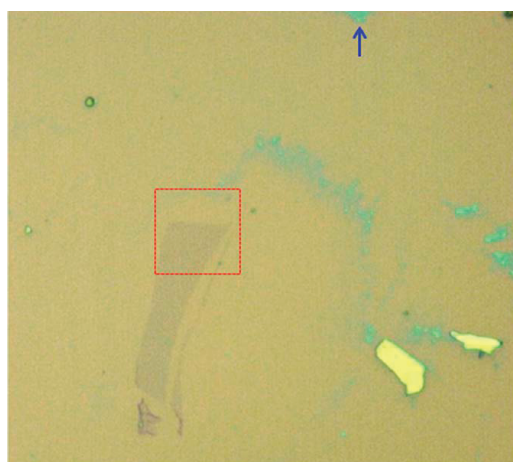


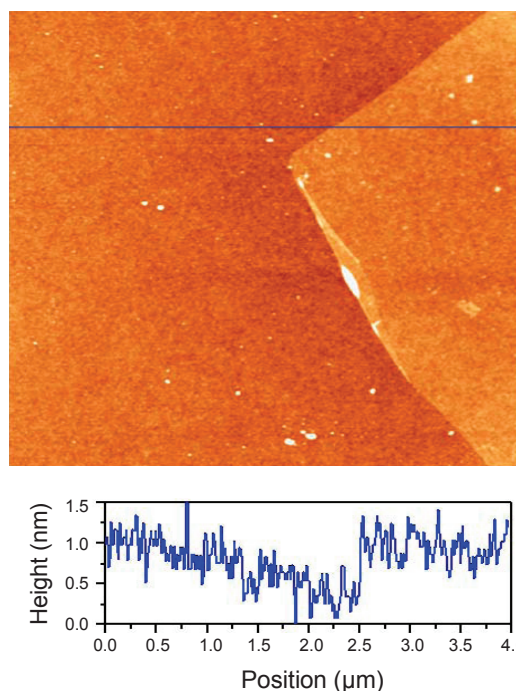
## Raman Spectroscopy Study of Annealing-Induced Effects on Graphene Prepared by Micromechanical Exfoliation

Jieun Song, Taeg Yeoung Ko, and Sunmin Ryu\*

Department of Applied Chemistry, Kyung Hee University, Yongin, Gyeonggi 446-701, Korea. \*E-mail: sunryu@khu.ac.kr  
Received June 18, 2010, Accepted July 13, 2010



**Figure S1.** Optical micrograph of a graphene sample taken after thermal annealing in Ar atmosphere at 300 °C for 2 hrs. The AFM image in Figure 1 was taken from the area within the dotted square. The arrow points to the adhesive residue where the Raman spectrum in Figure 4 was taken.



**Figure S2.** (a) AFM image of pristine single layer graphene on SiO<sub>2</sub>/Si substrate. The image size is 4 × 4 μm<sup>2</sup>. (b) Line profile taken across graphene.